Search Notes			

Application/Control No.	Applicant(s)/Patent under Reexamination		
10/812,627	CHEN, EDDIE		
Examiner	Art Unit		
Marie Patterson	3728		

	SEAR	CHED	
Class	Subclass	Date	Examiner
036	4, 12	1/31/2006	nos
1	14,10	1	1
	55, 21		
	43, 44		
	17R		1
036	17PW	1/31/2006	moop

INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
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